ITC a BIG Success

The 1986 International Test Conference is now history and, by all measures, it was a resounding success. For the first time, ITC was held in Washington, D.C., after many years in Philadelphia. The new location allowed the addition of many new exhibitors. In fact, 23 additional companies were represented, for a total of 85.

Conference attendance also increased to over 3600, a gain of more than 17% from 1985. Lastly, tutorial attendance rose from 412 to 575, a gain of 40%. In this year of austerity for the electronics industry, this surge in participation was a pleasant surprise for all involved. Peter Bronecke, conference chairman, attributed the gains to "ITC's superior technical program." Others felt that a new emphasis on and awareness of testing and its impact upon product quality were factors. Lastly, the move to Washington helped to attract some new participants.

Everyone involved is now looking forward to next year’s conference, to be held September 1-3, 1987. The announced theme is Integration of Test with Design and Manufacturing. Contact the conference office at (201) 895-5260 for more information.

BIST WORKSHOP

The fifth annual IEEE Built-In Self-Test Workshop will be held March 11-13, 1987 on beautiful and warm Kiawah Island, South Carolina. Presentations will focus on chip, multi-chip assembly, and system-level BIST.

To facilitate better sharing of ideas, attendance will be limited to 70 persons. Those wishing to participate should contact the workshop chairperson as soon as possible:

Richard Sedmak
Self-Test Services
6 Lindenwold Terrace
Ambler, PA 19002 USA

(215) 628-9700

REMINDER

The IEEE Test Technology Technical Committee Newsletter has been merged with Design and Test magazine. If you are interested in remaining abreast of test-related activities during 1987, be sure to send your Design and Test subscription renewal to IEEE by year’s end.